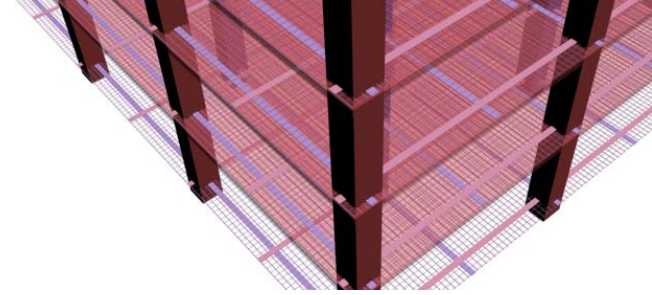
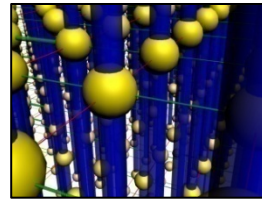
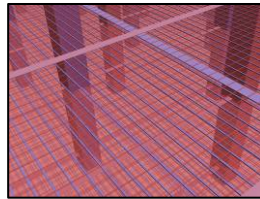
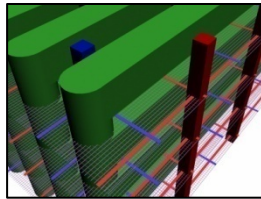
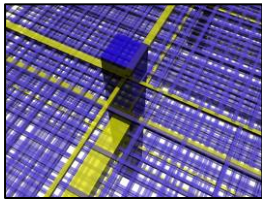




National Science Foundation
WHERE DISCOVERIES BEGIN



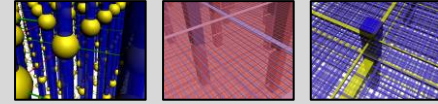
Power and Slew-aware Clock Network Design for Through-Silicon-Via (TSV) based 3D ICs



Xin Zhao and Sung Kyu Lim
School of Electrical and Computer Engineering
Georgia Institute of Technology
Atlanta, Georgia, U.S.A.

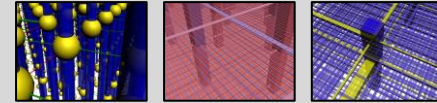


Outline



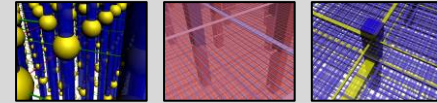
- **Introduction**
- **Problem formulation**
- **3D clock tree synthesis**
- **Simulation and discussions**
- **Conclusions**

Related works

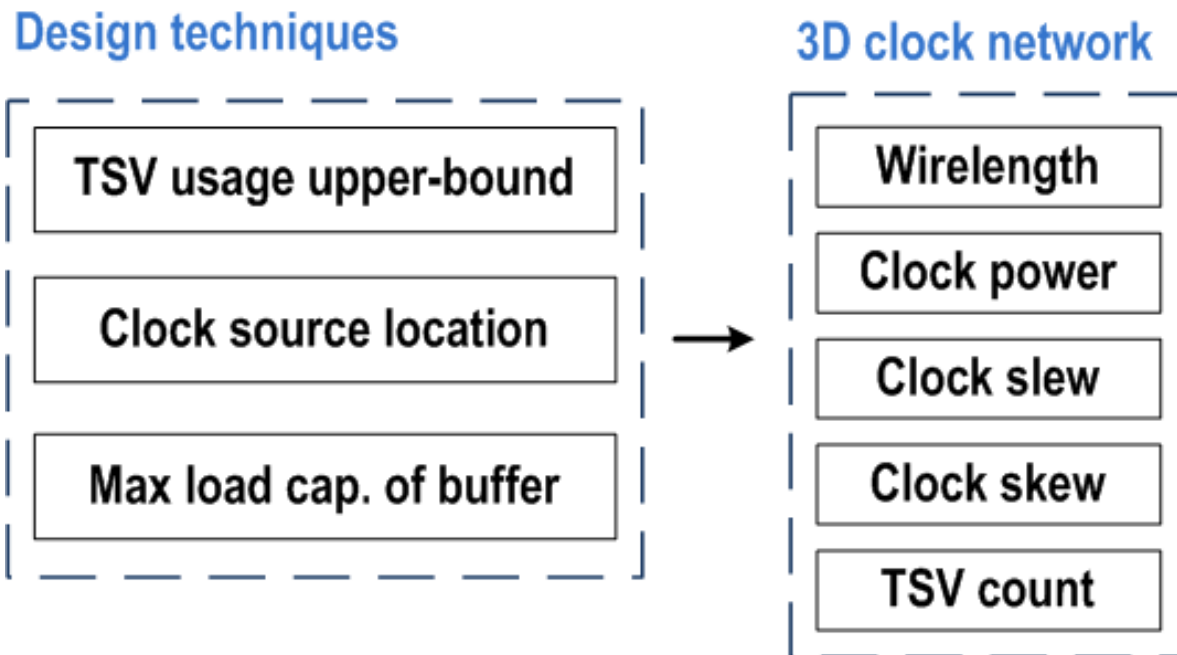


- **Through-silicon-via (TSV)**
 - Fabrication and characterization
 - Reliability issues [Ramm, etc. ECTC'08] [Wright, etc. ECTC'08]...
- **Low-power 3D clock network**
 - A fabricated 3D clock distribution network [Pavlidis, etc. CICC'08]
 - A separate layer of clock distribution network for power reduction [Arunachalam, etc. VLSI'08]
- **3D clock network design and optimization**
 - Thermal-aware 3D clock design, 3D clock routing algorithm [Minz, etc. ASPDAC'08]
 - Pre-bond testable 3D clock synthesis [Zhao, etc. ICCAD'09]

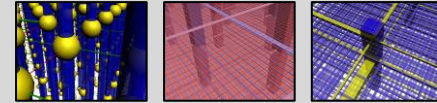
Contributions



- **The major goals**
 - Clock skew minimization
 - Clock slew control
 - Clock power reduction
- **Investigate the impact of design techniques on 3D clock network**



Electrical model and TSV usage



- **Electrical model**

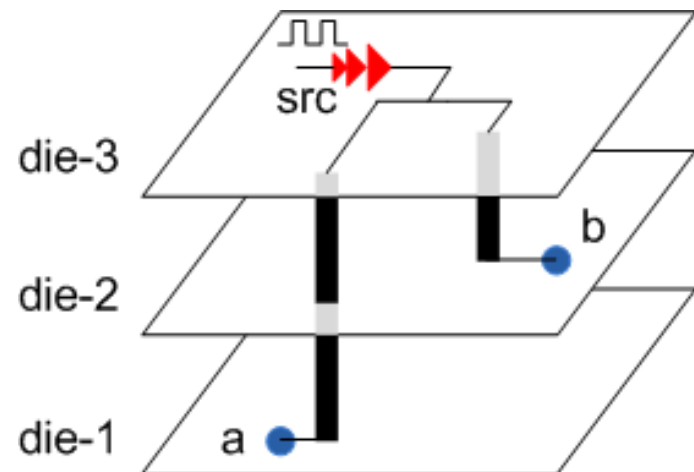
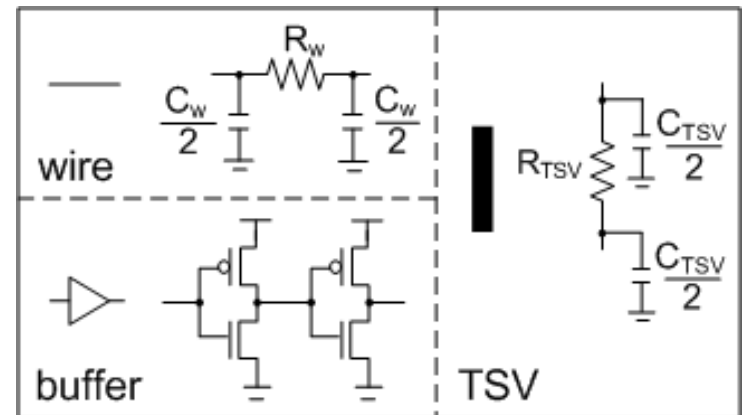
- Wire
- TSV
- Clock buffer

- **TSV upper bound**

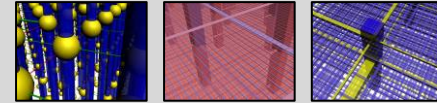
- Maximum number of TSVs allowed between adjacent dies

- **TSV count (#TSVs)**

- Total number of TSVs used in 3D tree
- Stacked-TSV

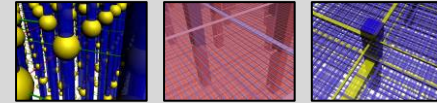


Problem formulation: 3D clock tree synthesis



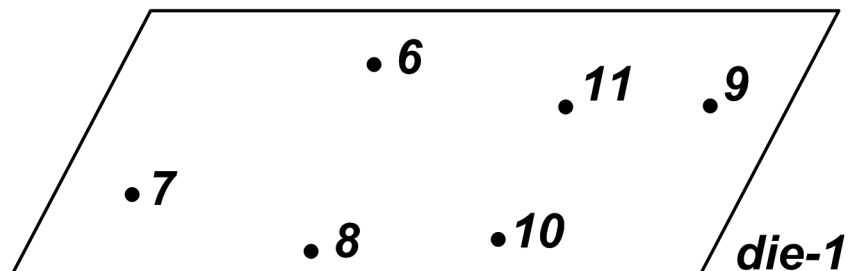
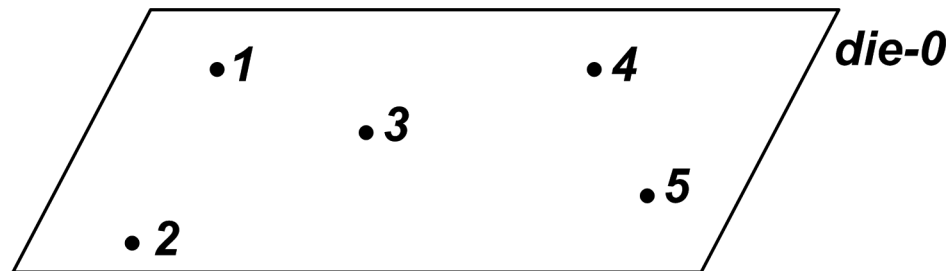
- **Input**
 - Sink set (N dies), clock source location
 - Upper bound of TSV usage
 - Slew constraint
- **Output**
 - **Zero-Elmore-skew** 3D clock tree
- **Object**
 - Zero-Elmore-skew
 - Minimize wirelength, clock power
- **Constraint**
 - Maximum slew
 - Upper bound of TSV usage

3D clock tree design flow



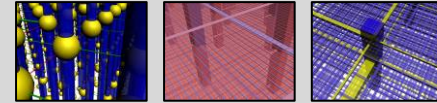
- **Input:**

- a set a sinks on N die
- Upper bound of TSV

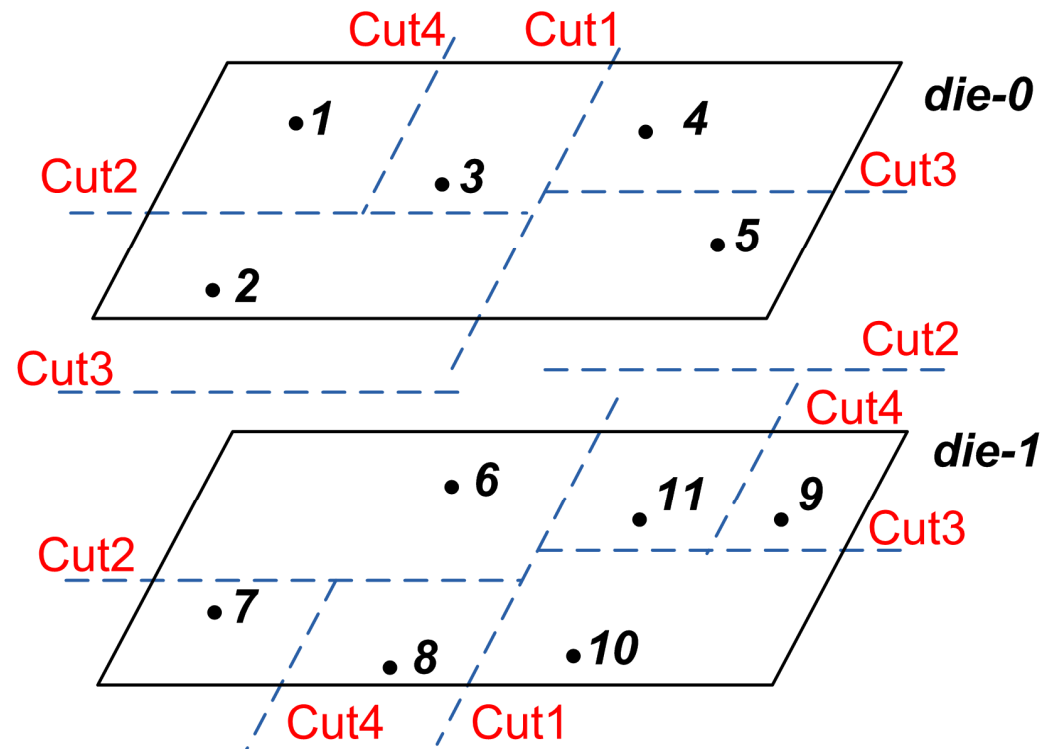
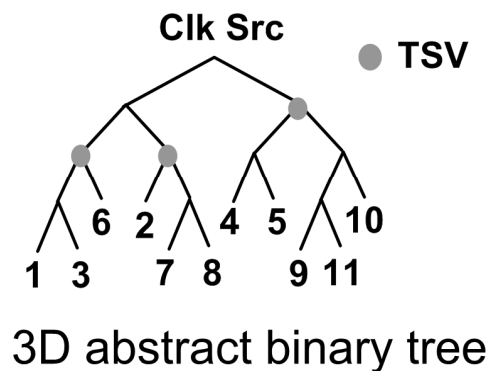


Upper bound of TSV = 3, clock source locates on die-0

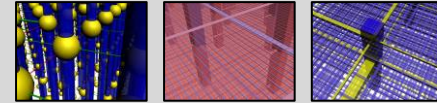
3D clock tree design flow (cont.)



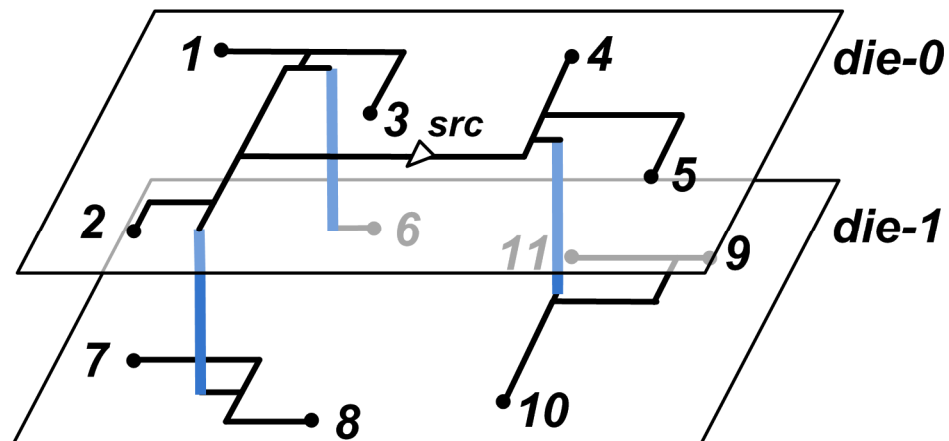
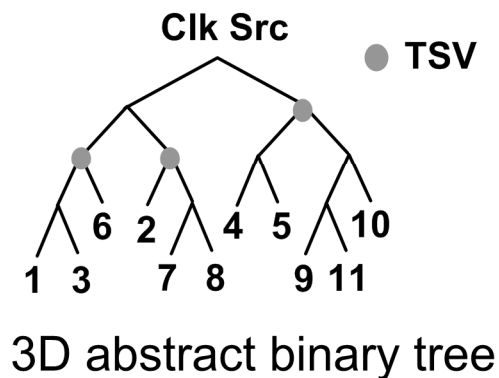
- Step-1:
 - Recursive top-down partition
 - 3D Method of Means and Medians (3D-MMM)
 - 3D abstract binary-tree generation



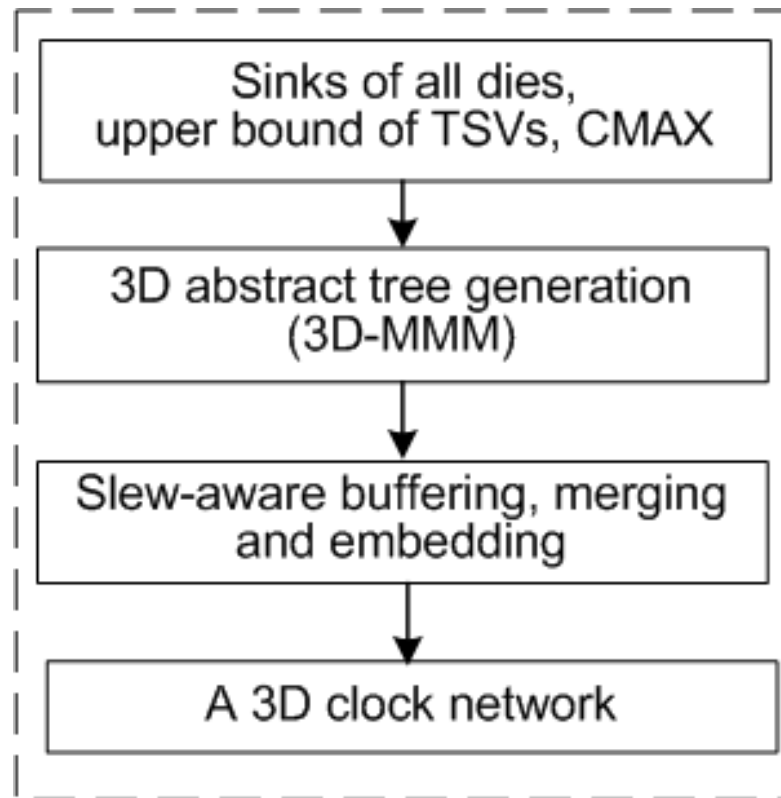
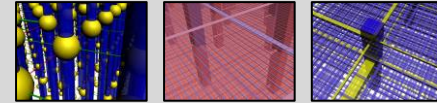
3D clock tree design flow (cont.)



- **Step-2:**
 - Merging and slew-aware buffering, embedding
 - 3D clock tree with multiple TSVs
- **Unique property of 3D clock tree**
 - A complete tree + many sub-trees

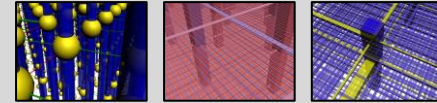


3D clock routing algorithm



3D clock tree synthesis

3D-MMM and 3D abstract tree

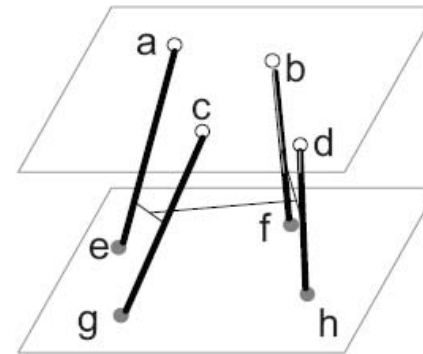
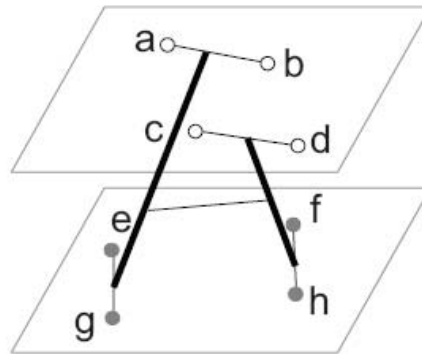
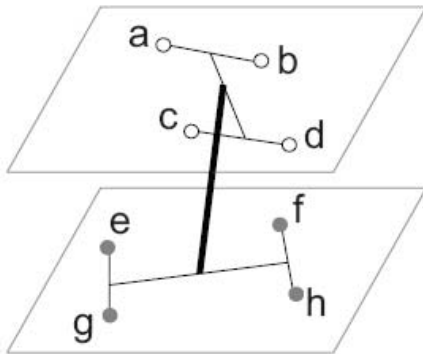
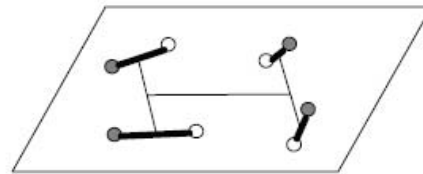
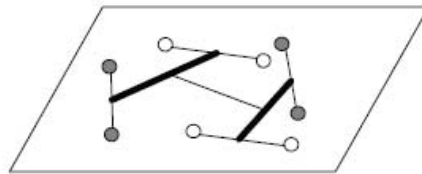
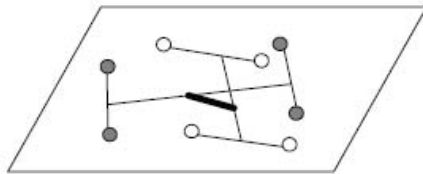


TSV=1

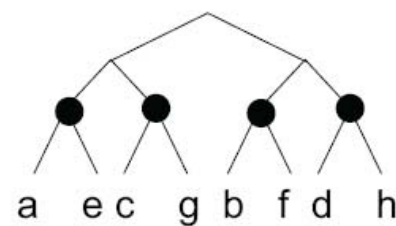
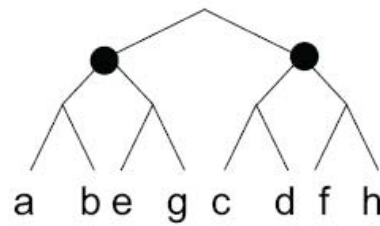
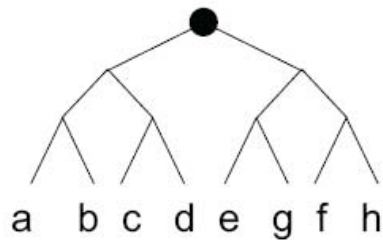
TSV=2

TSV=4

2D version

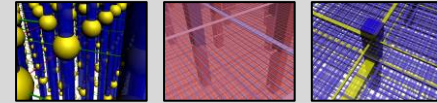


3D version

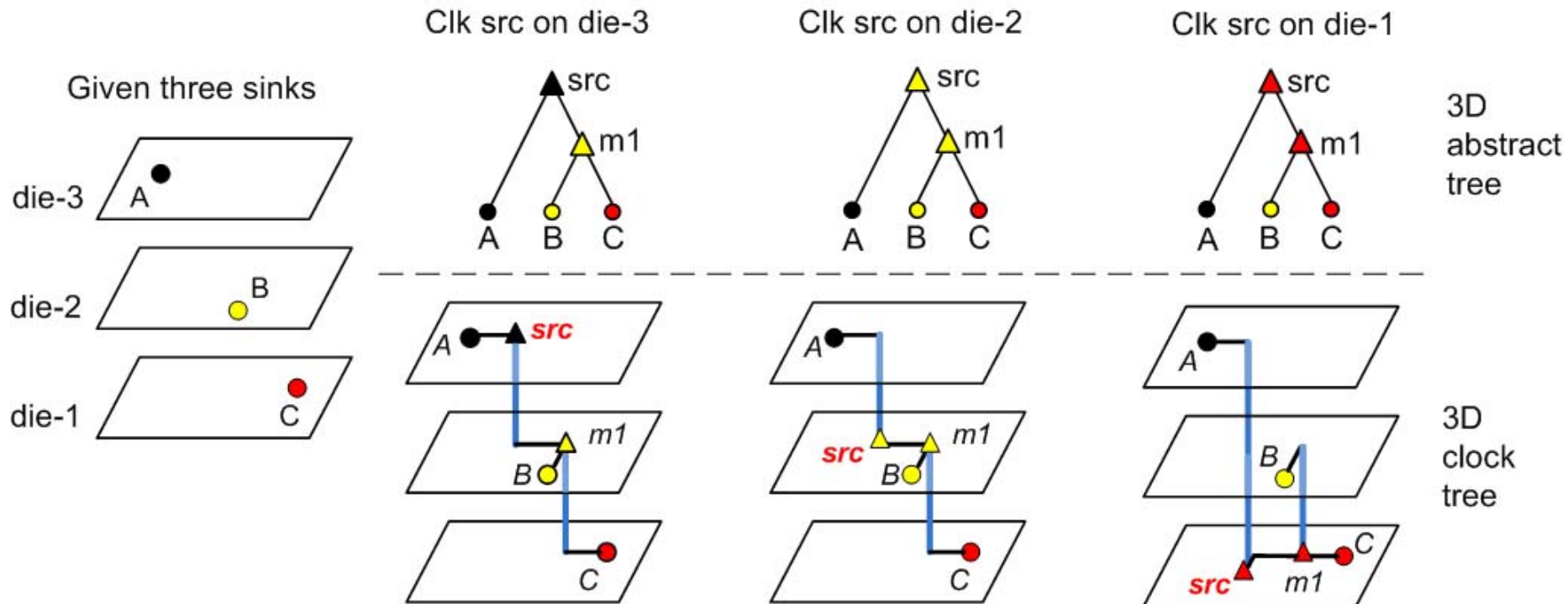


3D abstract tree

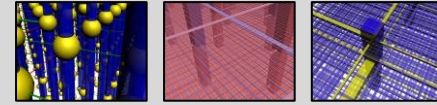
3D-MMM and 3D abstract tree (cont.)



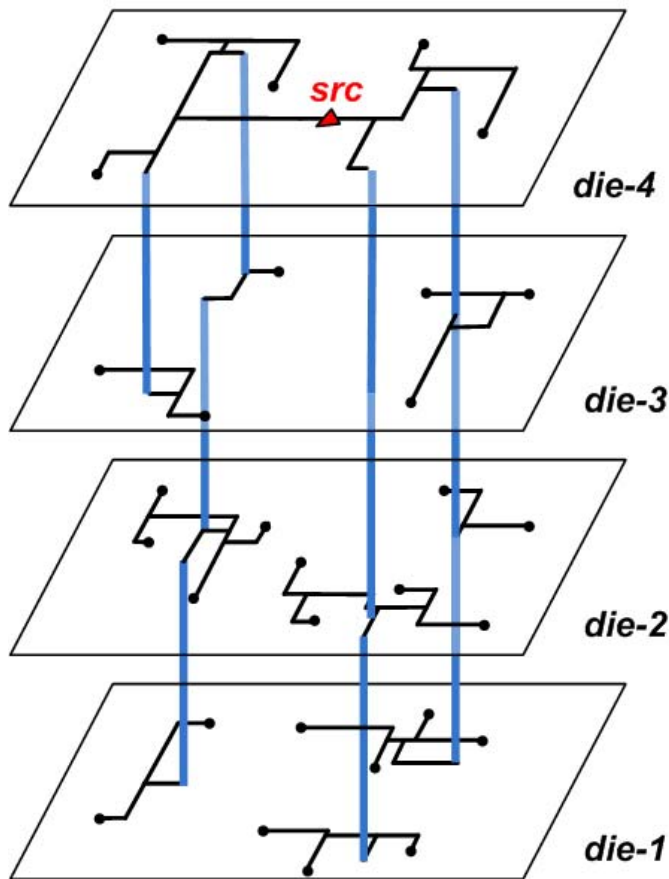
- 3D abstract tree for the N-die stack
 - N-colored binary tree
 - Clock source location



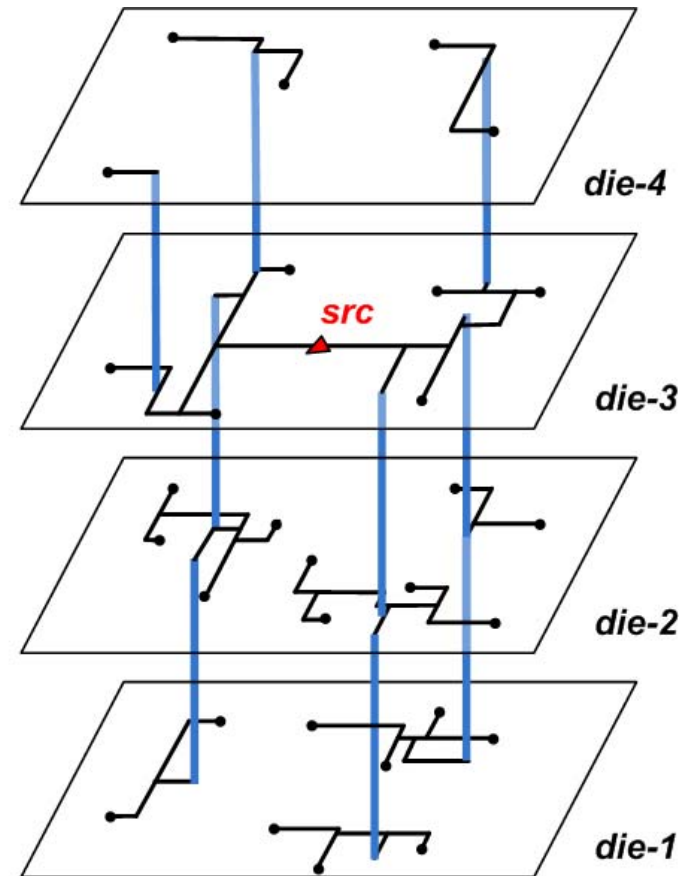
3D clock tree in multiple-die stack



- A complete tree + many sub-trees

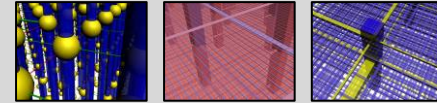


Four-die 3D clock tree, src on die-4



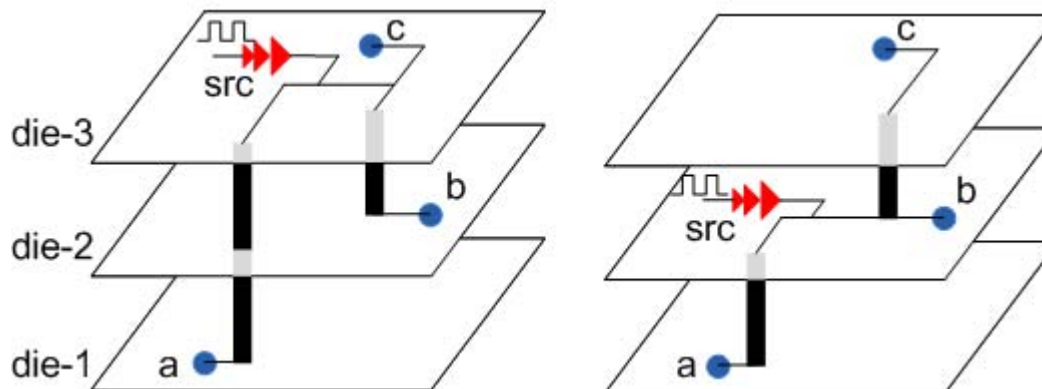
Four-die 3D clock tree, src on die-3

Clock source location

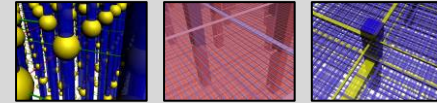


- Clock source on middle die tends to reduce #TSVs and wirelength
- Theoretical maximum TSV usage:
 - M sinks evenly distribute on N dies, clock source locates on die-s

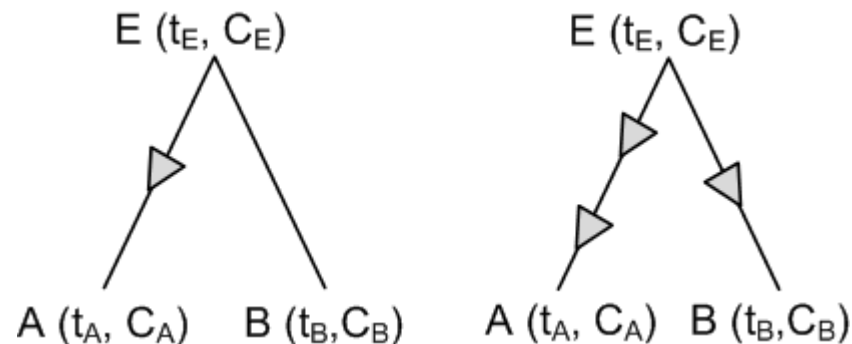
$$\frac{M}{N} \times \left(\sum_{i=1}^{s-1} (s-i) + \sum_{i=s+1}^N (i-s) \right)$$



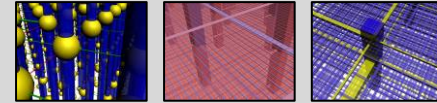
Buffering and merging



- **Goal**
 - Slew control
 - Maximum loading capacitance (C_{MAX}) of clock buffers
 - Wirelength reduction
- **Object**
 - Zero-Elmore skew
 - Clock power minimization



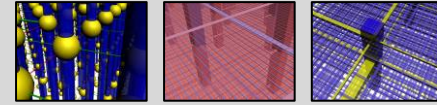
Detail experiment settings



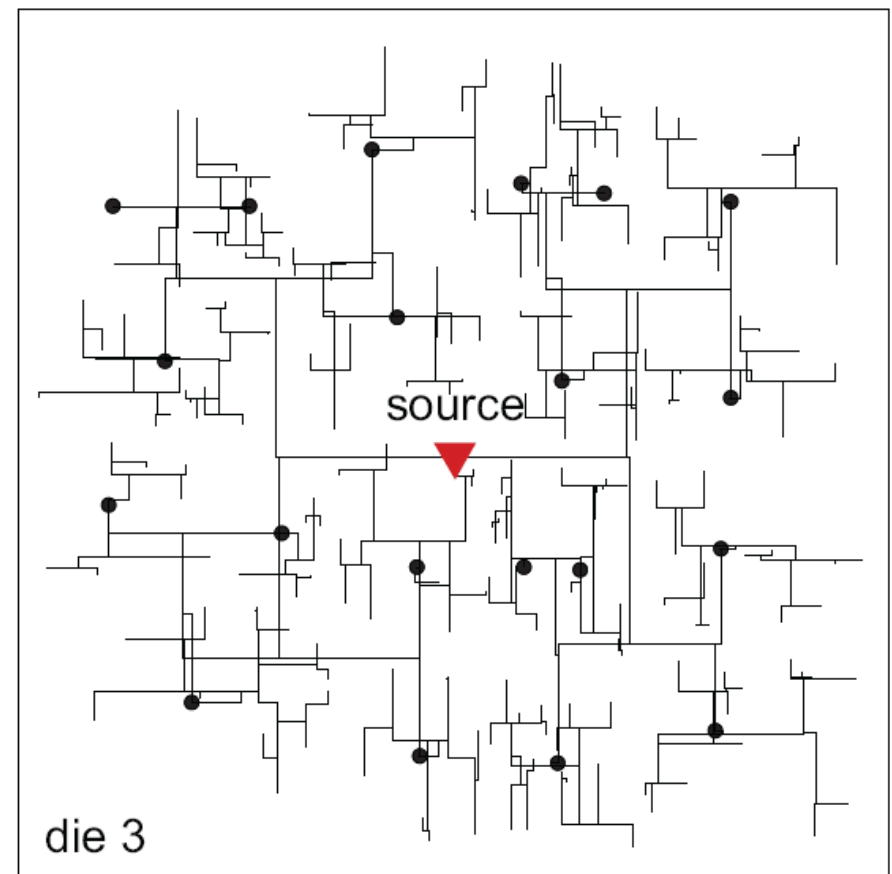
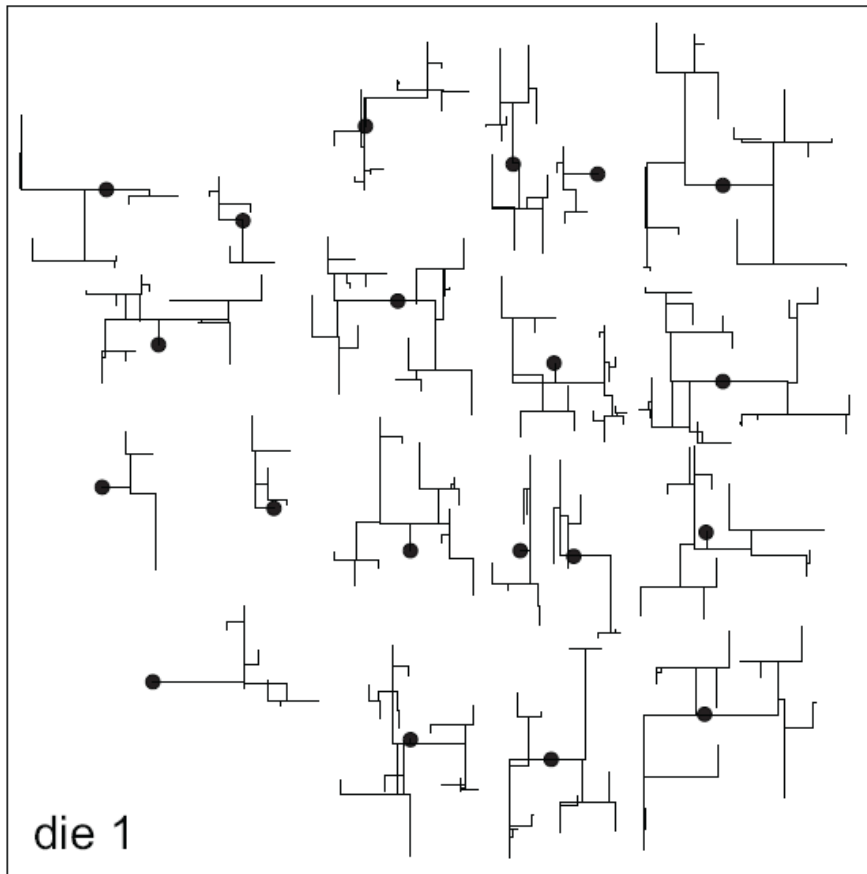
- 45nm technology:
 - Frequency = 1GHz, $V_{dd} = 1.2V$
 - Clock slew < 10% of clock period (C_{MAX} = 300fF)
 - Clock skew < 3%~4% of clock period
 - Wire: $R = 0.1 \Omega/\mu m$, $C = 0.2 fF/\mu m$
 - Buffer: $R_d = 122 \Omega$, $C_L = 24 fF$, $t_d = 17 ps$
 - TSV: $R_{TSV} = 0.035 \Omega$, $C_{TSV} = 15.48fF$
 - 10 μm X 10 μm , via-last
 - Thinned-die height = 20 μm
- Results are from SPICE simulation
 - Skew, slew, power
- We use two cases: four-die and six-die

| Circuits | # Sinks |
|----------|---------|
| r1 | 267 |
| r2 | 598 |
| r3 | 862 |
| r4 | 1903 |
| r5 | 3101 |

Sample 3D clock trees

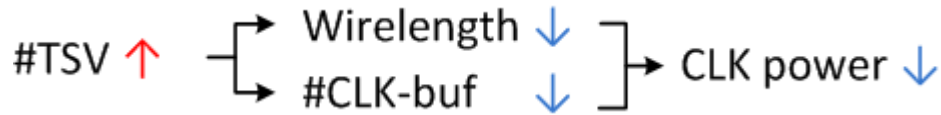
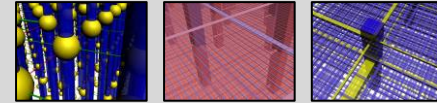


r5, six-die

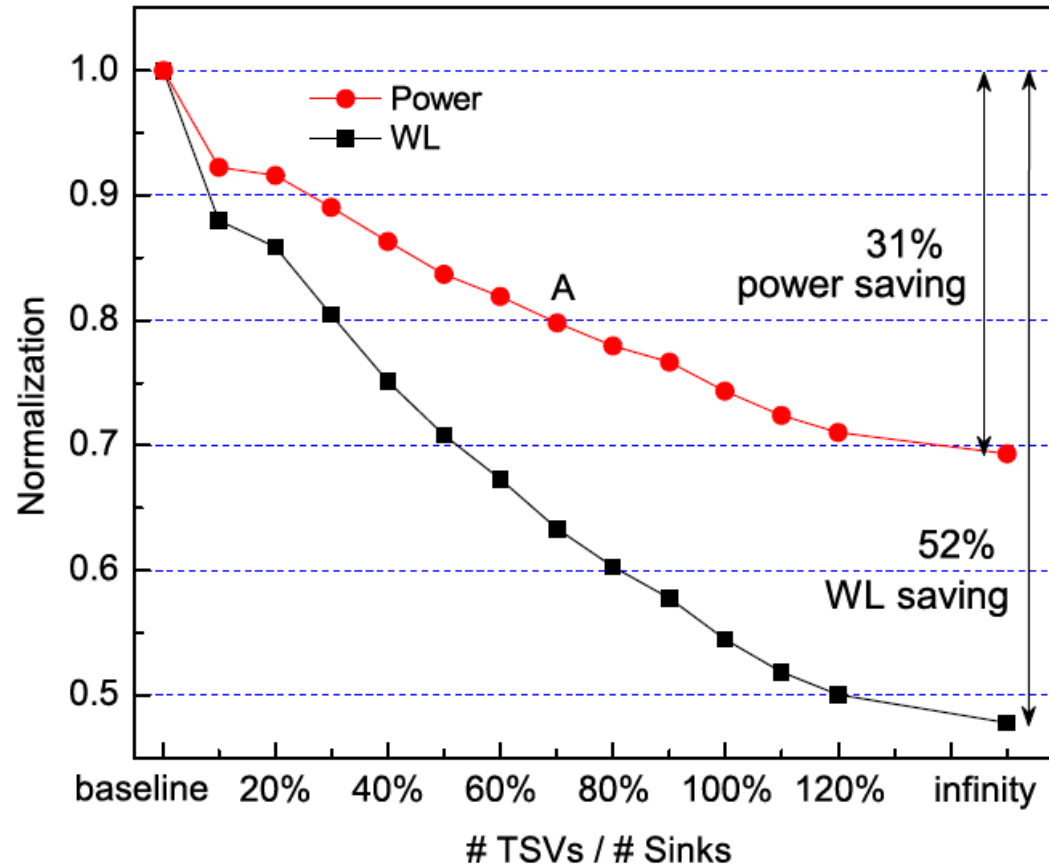


#TSVs = 20

Impact of TSV bound on wirelength and power

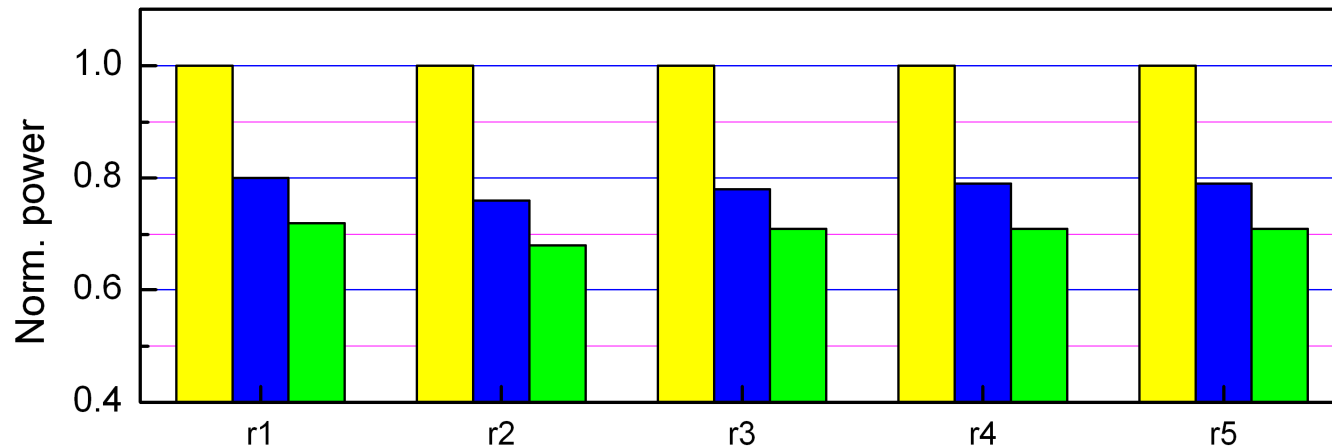
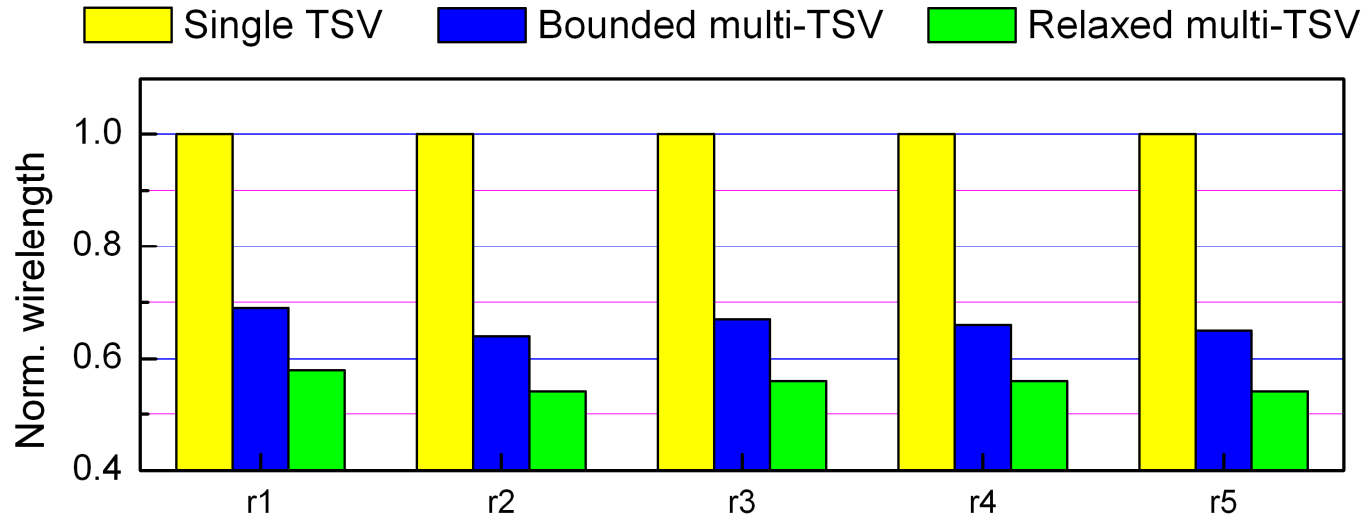
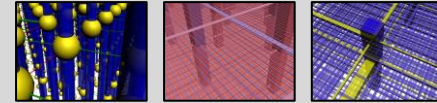


r5, six-die



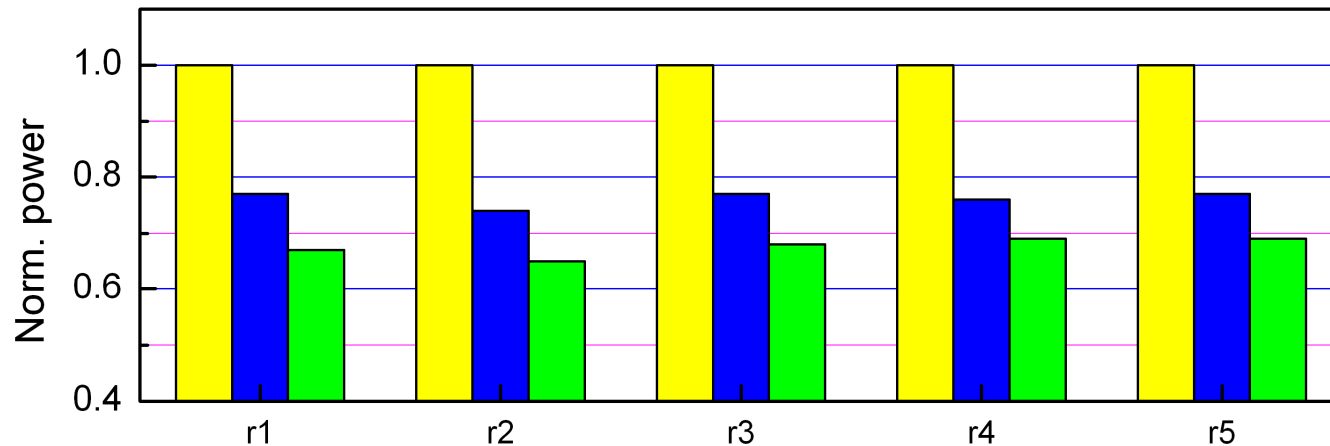
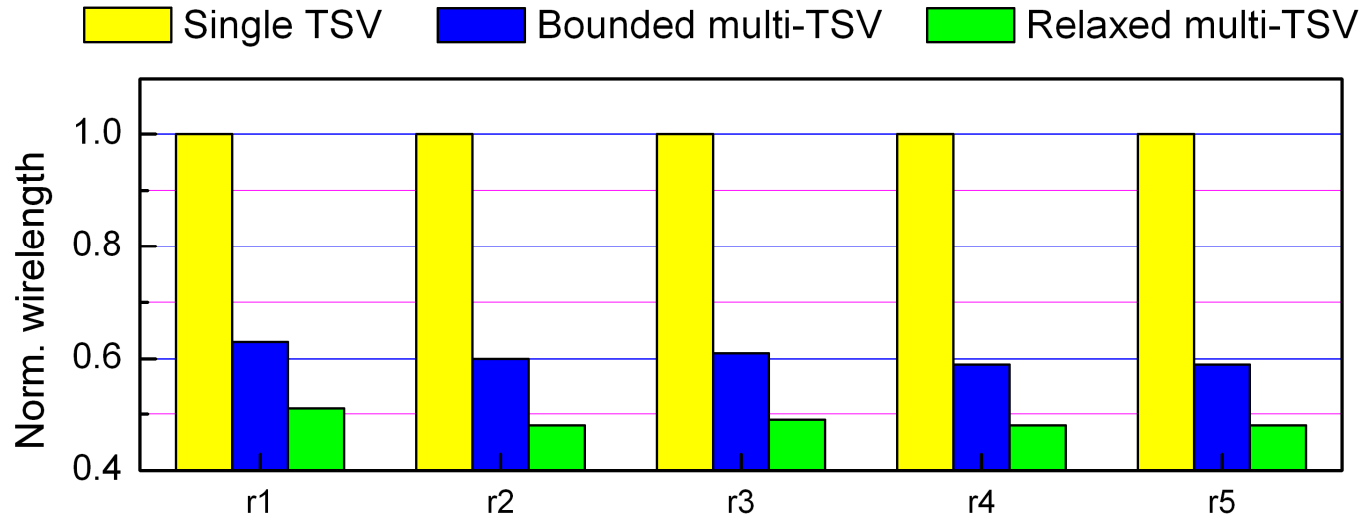
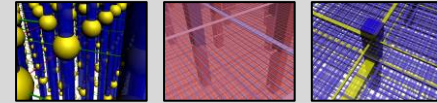
Point A: 20% power saving, TSV bound $\geq 70\%$ of #sinks

Multi-TSV vs Single-TSV: four-die stack



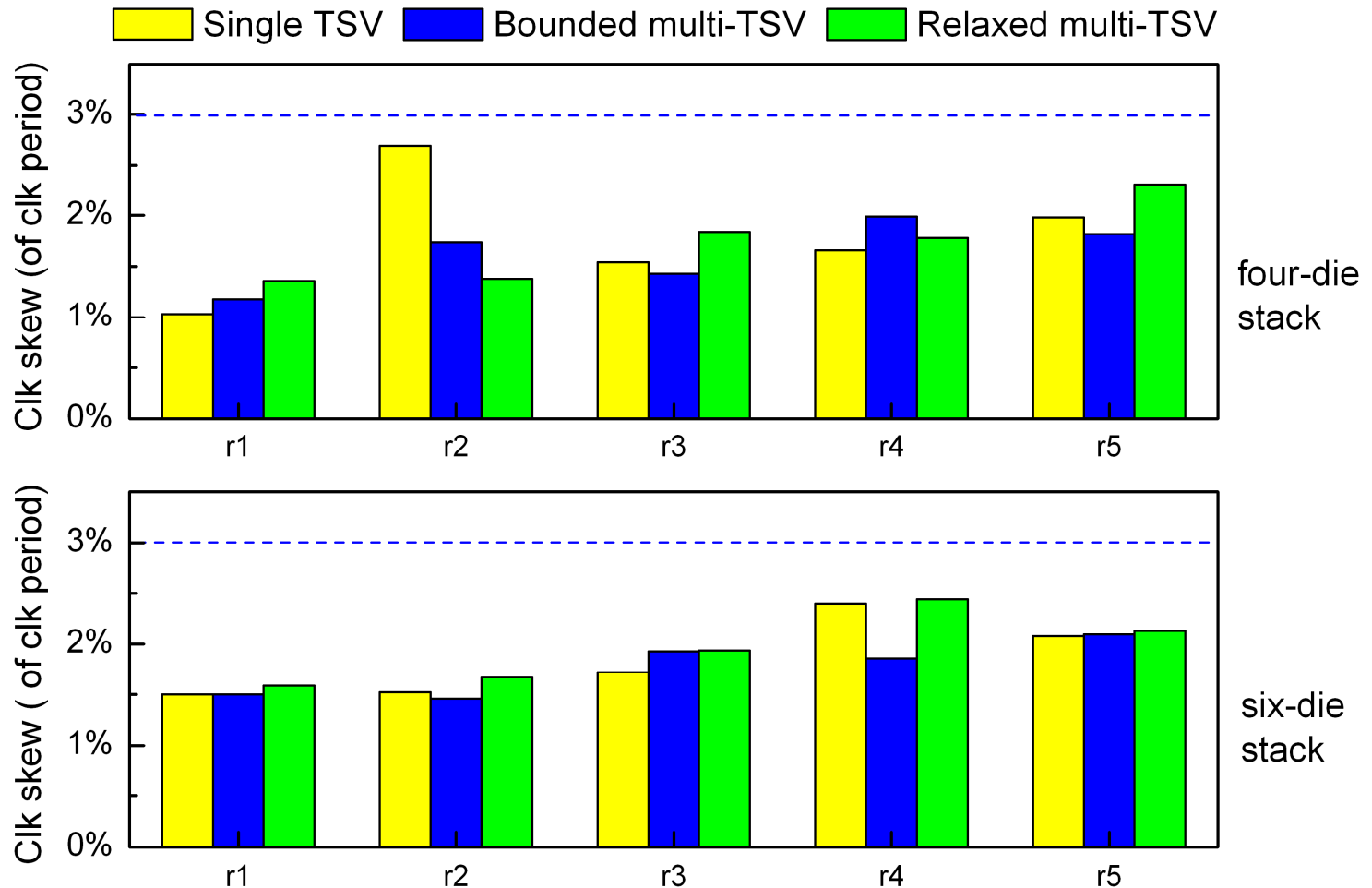
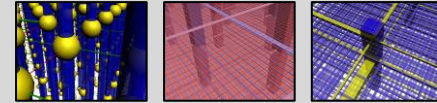
| | | | | | |
|----------------|-----|-----|-----|------|------|
| #TSVs (Bnd): | 139 | 309 | 432 | 1003 | 1631 |
| #TSVs (Relax): | 265 | 579 | 819 | 1893 | 3097 |

Multi-TSV vs Single-TSV: six-die stack

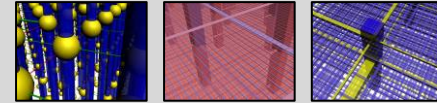


| | | | | | |
|----------------|-----|-----|------|------|------|
| #TSVs (Bnd): | 222 | 483 | 701 | 1594 | 2588 |
| #TSVs (Relax): | 399 | 908 | 1301 | 2980 | 4782 |

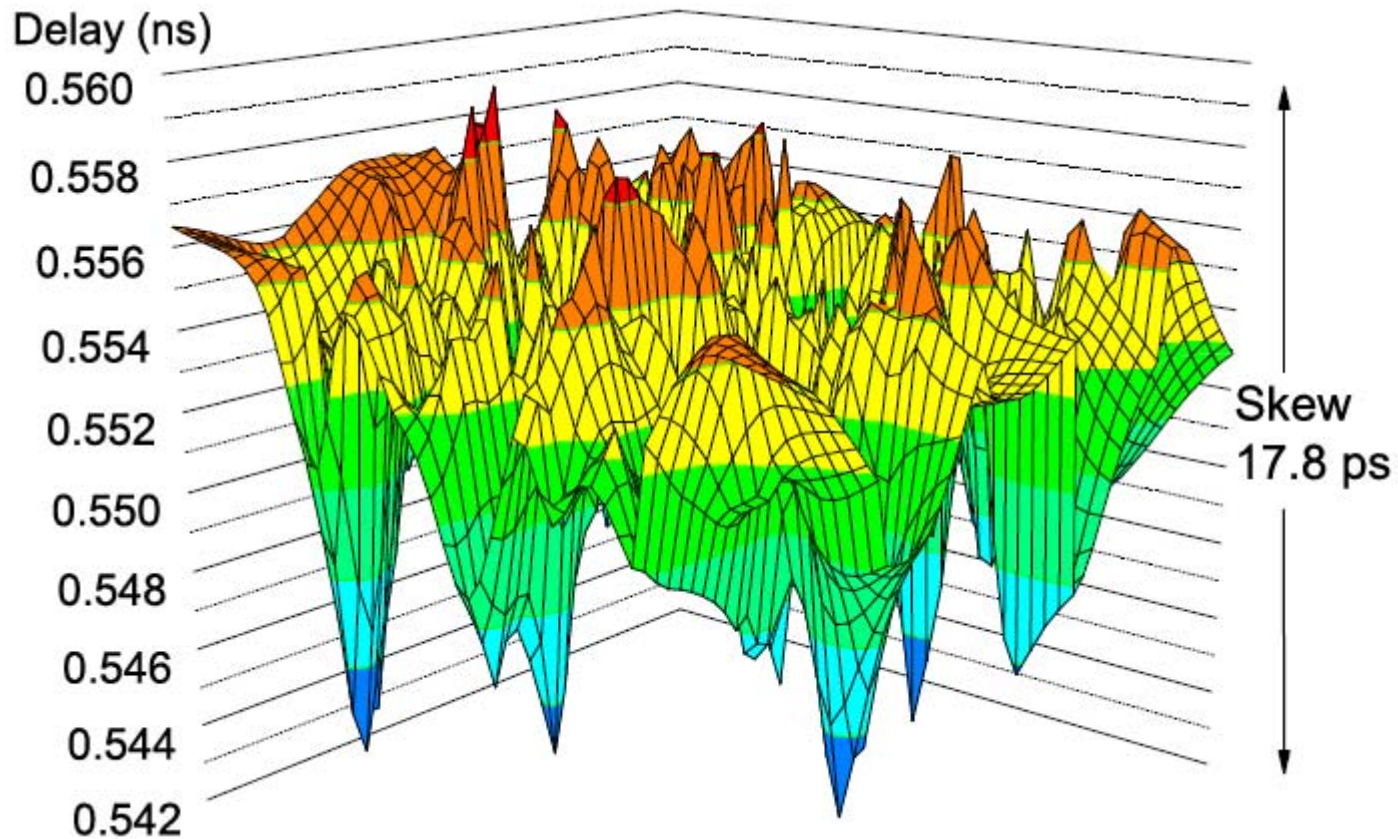
Clock skew in four- and six- die stack



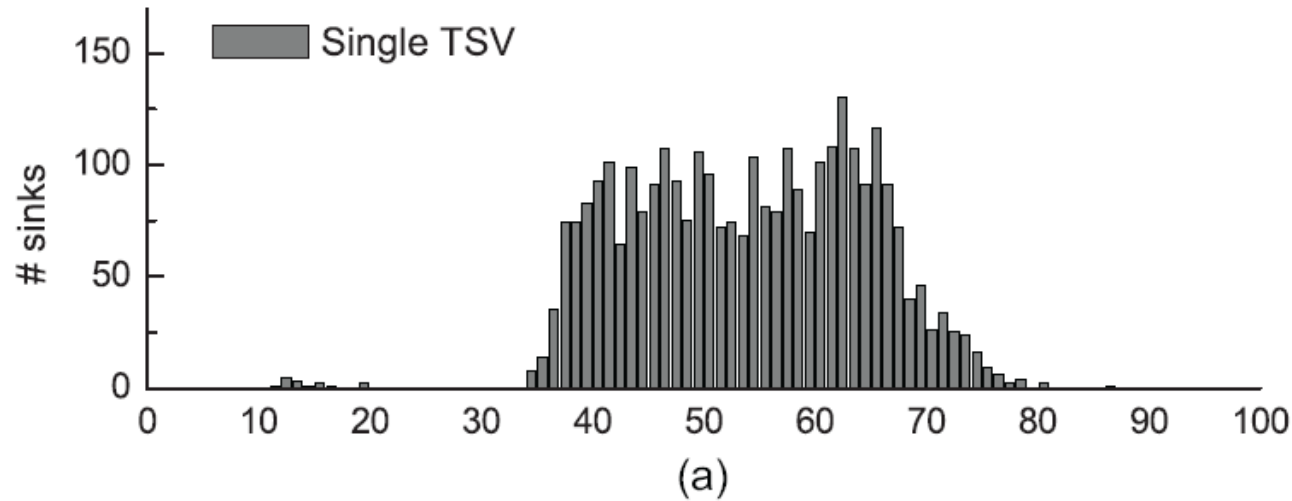
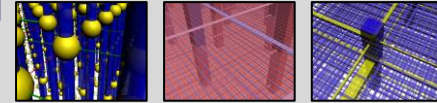
Spatial distribution of clock delay



r5, six-die

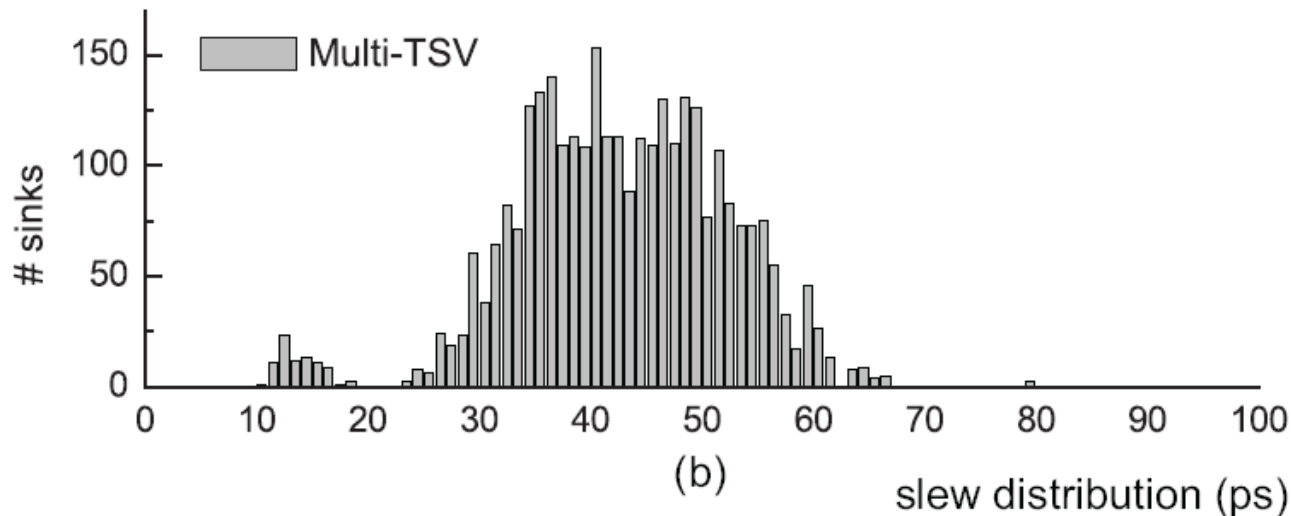


Impact of TSV bound on slew distribution



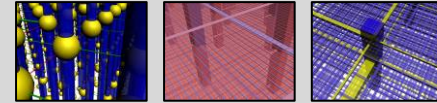
r5, six-die
C_{MAX}=300fF

[11.4ps, 86.2ps]
Avg. 53.9ps
#Bufs: 2933

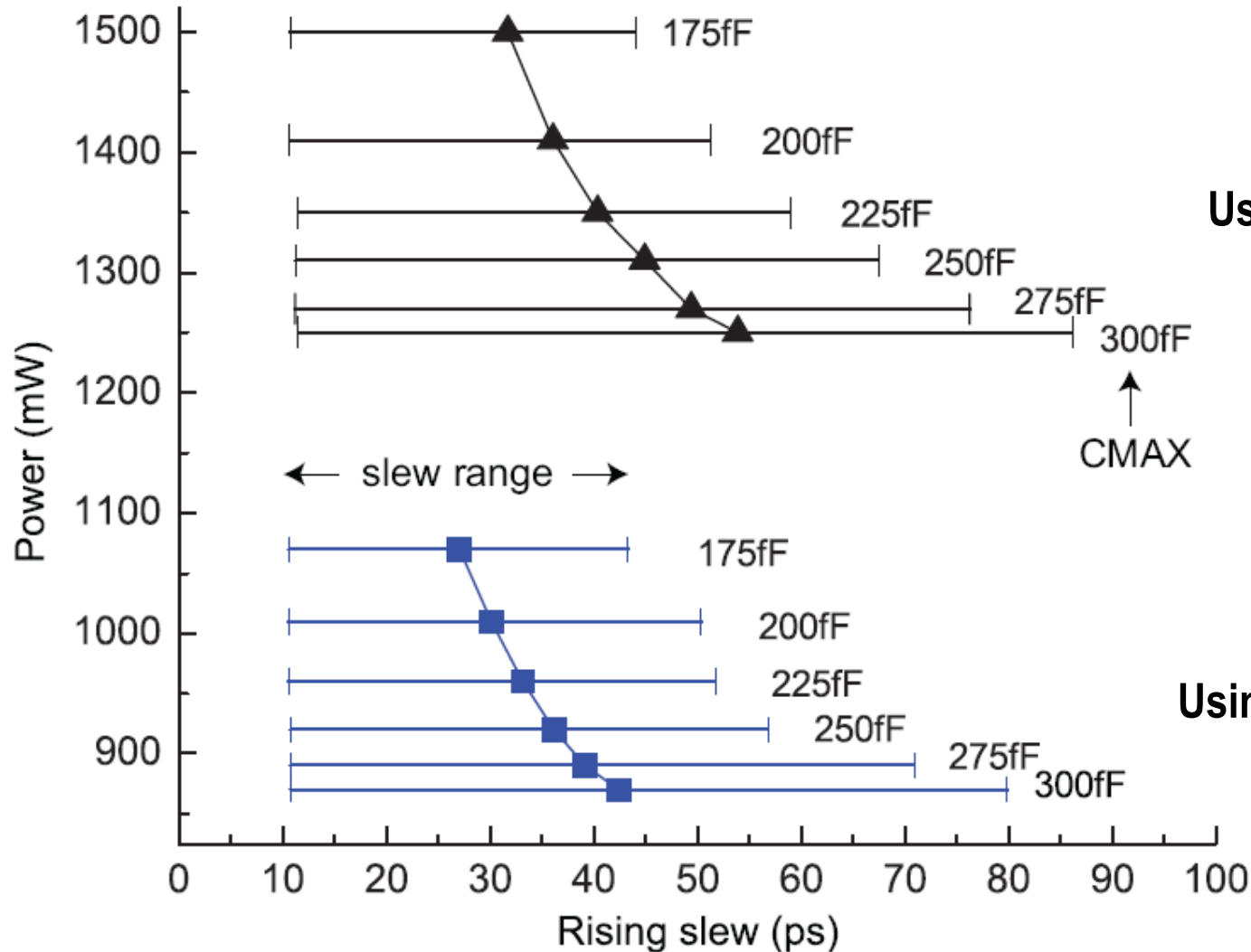


[10.9ps, 79.6ps]
Avg. 42.6ps
#Bufs: 2638

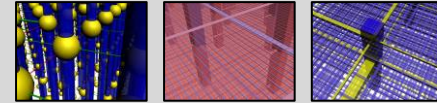
Impact of CMAX on slew variations



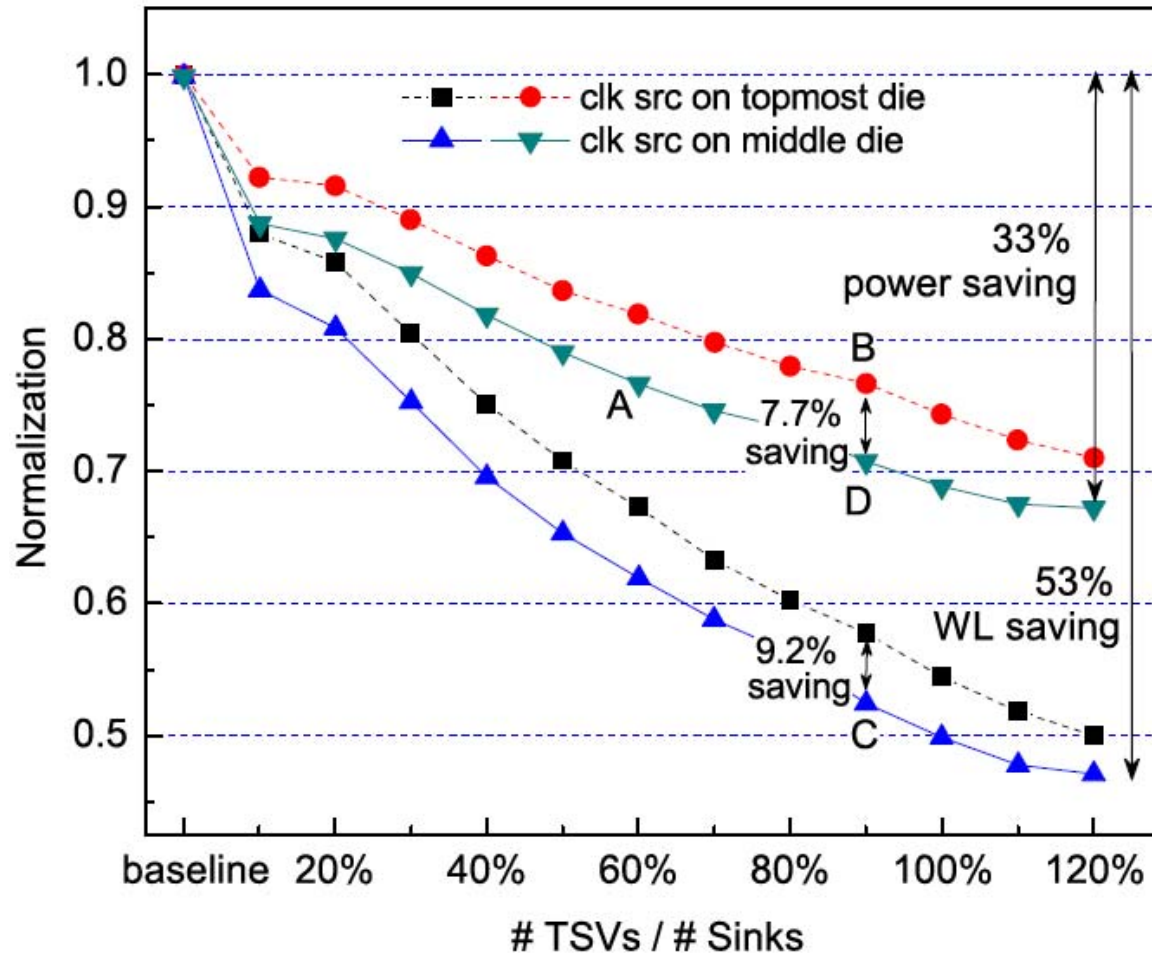
r5, six-die



Impact of clock source location on power and wirelength

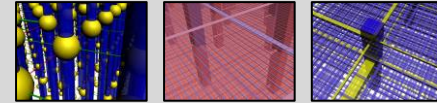


r5, six-die

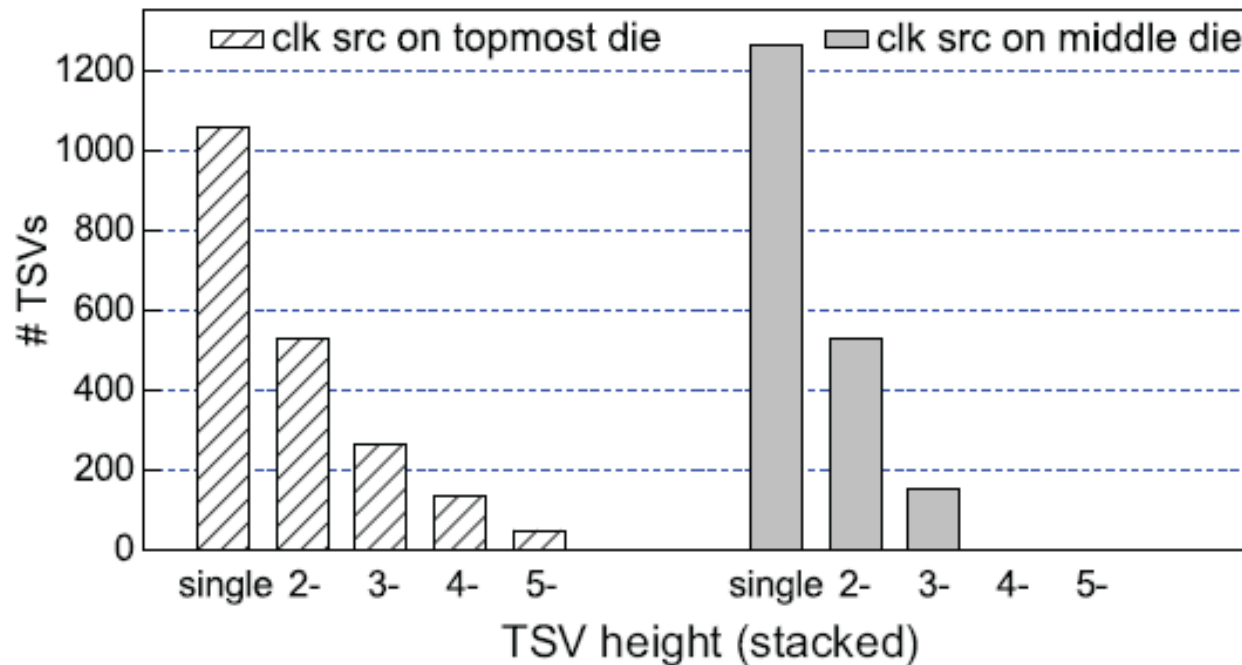


A uses 33% fewer TSVs than B

Distribution of stacked-TSV heights



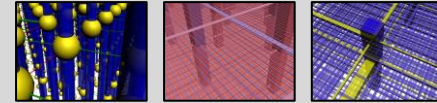
r5, six-die



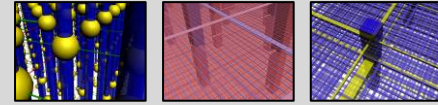
#TSVs = 3720

#TSVs = 2791

Conclusions



- **Explored design optimization techniques for reliable, low-power, low-slew 3D clock network design.**
- **Using multiple TSVs helps to reduce wirelength and power. Multi-TSV also has better control on slew variations.**
- **Smaller CMAX efficiently lowers the clock slew.**
- **Clock source location affects wirelength, power and TSV usage of the 3D clock network. Middle-die sourcing policy reduces the TSV usage under the same power budget.**



Thank you